

FORM PTO-1449 (modified)
 To: U.S. Department of Commerce
 (PW FORM PAT-1449)
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Atty. Dkt. No.	M# 307474	Client Ref. P-1796.000-US
Applicant: KROON et al.		
Appln. No.: 10/748,751		
Filing Date: December 31, 2003		
Examiner: Peter B. Kim Group Art Unit: 2851		

Date: March 23, 2006

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U.S. PATENT DOCUMENTS

Examiner's Initials*	Document Number	Date MM/YYYY	Name (Family Name of First Inventor)	Class	Sub Class	Filing Date (if appropriate)
AR						
BR						
CR						
DR						
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FR						
GR						
HR						
IR						
JR						
KR						
LR						
MR						
NR						

FOREIGN PATENT DOCUMENTS

	Document Number	Date MM/YYYY	Country	Inventor Name	English Abstract	Translation Readily Available	
					Enclosed	No	Enclose
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PK	PR 1 037 036 A1	09/2000	Europe	Trace Analytical			
PK	QR 0 874 283 A3	01/2000	Europe	Nikon Corporation			
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OTHER (Including in this order Author, Title, Periodical Name, Date, Pertinent Pages, etc.)

PK	YR	International Search Report issued for PCT Application PCT/NL2004/000927 on December 19, 2005.
	ZR	
	AAR	
	BBR	
	CCR	

Examiner *Peter B. Kim* Date Considered: *4 / 1 / 06*

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